



Application and Theory of Multimedia Signal Processing Using Machine Learning or Advanced Methods

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Message from the Guest Editor

Deep learning technology emerged as a new breakthrough in the fields of data mining and AI, and has proven useful in both data analysis and application. In addition, deep learning technology has made great progress in the area of multimedia. Deep learning is a field of machine learning that is applied in smart phones for face recognition and voice commands. Meanwhile, deep learning technology contributes to the development of algorithms for the safety and security of multimedia data and the development of new applications.

This Special Issue will share the achievements of key researchers and practitioners in academia, as well as in the industry, dealing with a wide range of theoretical and applied problems in the field of multimedia. Authors are encouraged to submit contributions in any related areas.

In this Special Issue we welcome both original research papers and review articles on diverse topics such as:

- image and video application
- speech recognition
- information security
- pattern recognition
- human interaction
- biometric recognition





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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